

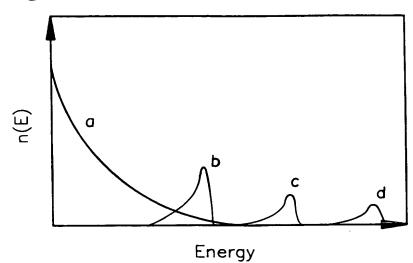
/: /: ' Discharge gap 0.1—1µm

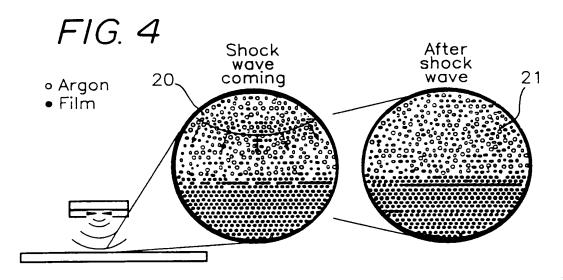
, 15

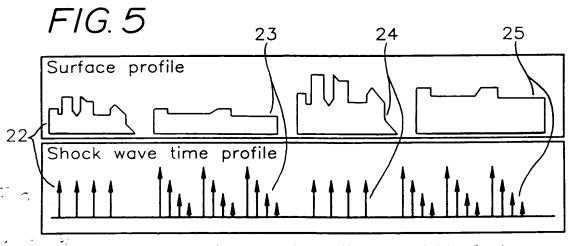
F1G. 6

	Atomic	Melt.	Boiling	Critical	Critical	Heat of	Heat
Liquid	Nun	point	point	Temp.	Pressure	Vaporisat.	Capacity
		×	· ·	₹	[Bar]	[10 ³ JK ⁻¹ kg ⁻¹]	[JK-1 kg-1]
H2	-	13.8	20.3	33.3	17	310	14200
N ₂	7	63.0	77.4	126.2	34	200	1040
02	8	54.8	90.2	154.6	51	213	920
F2	6	55.5	85.4	144.0	57	316	750
Ne	10	24.5	27.0	54.0	27	86	1030
Ar	18	83.8	87.3	150.8	48	158	520
Cl2	17	171.6	239.1	417.0	77	282	500
Kr	36	116.6	120	209.4	55	108	I
Xe	54	161.3	165.1	289.7	29	102	1
							The second secon

FIG. 3







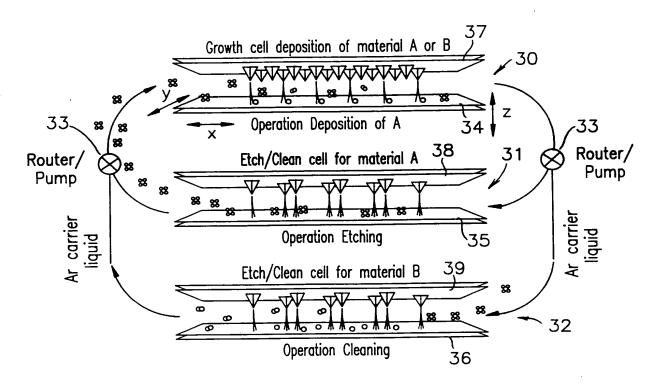
1st Deposition stage fluxing of material

1st Annealing stage

2nd Deposition stage fluxing of material

2nd Annealing stage

FIG. 7



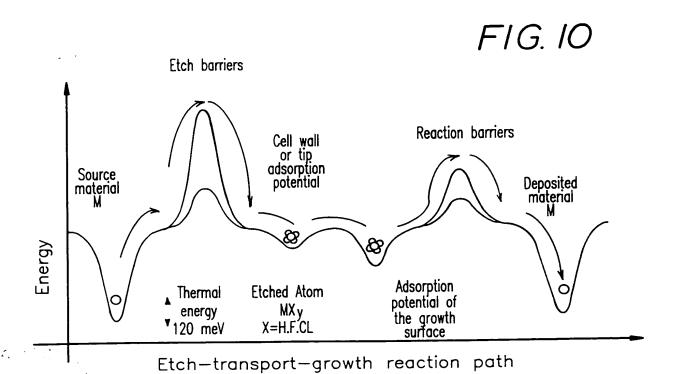
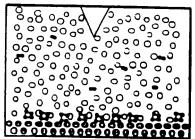
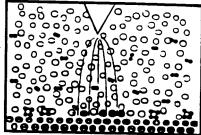


FIG. 8(a)



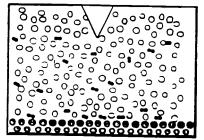
Before nanodischarge Physisorption of etched resource atom

FIG. 8(b)



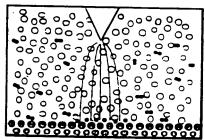
Weak nanodischarge for electron induced dissociative chemisorption of etched resource atom or deposition

FIG. 9(a)



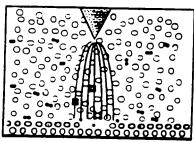
Before nanodischarge Physisorption of etchant molecules

FIG. 9(b)



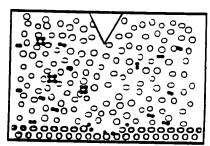
Weak nanodischarge for electron induced dissociative chemisorption

FIG. 9(c)



Strong nanodischarge Electron induced chemical etching

FIG. 9(d)

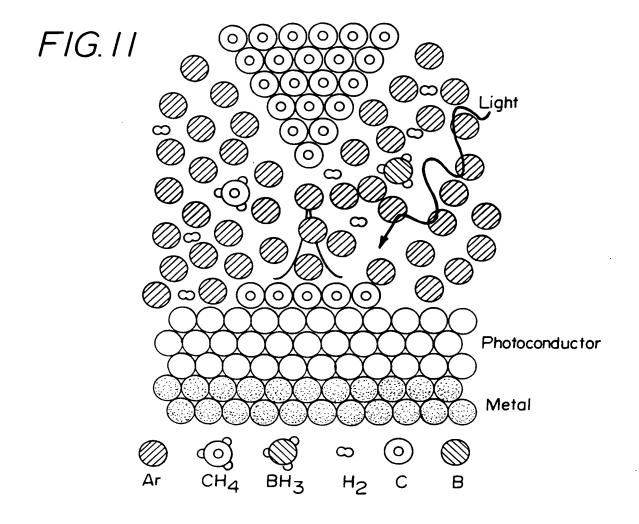


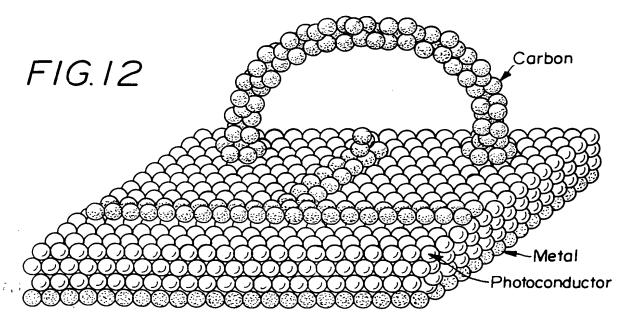
After nanodischarge re-physisorption of etchant molecules

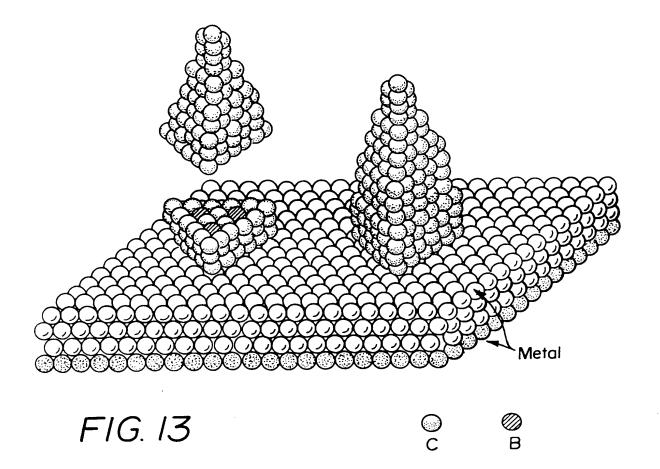
 $T = 80 - 150^{\circ} \text{K}$ Pressure = 1.0-50 Bar

- Argon

- Etchant molecule







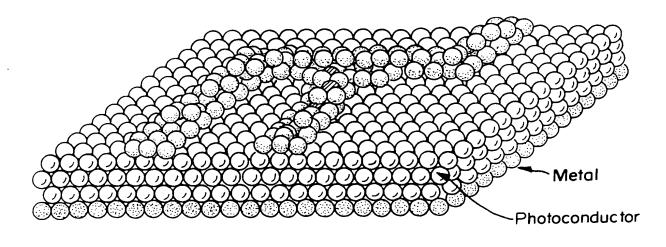


FIG. 14

